High Frequency, Single Chip, One-output Clock Generator



Features

- Any frequency between 115 MHz to 137 MHz accurate to 6 decimal places of accuracy
- Operating temperature from -40°C to 85°C. Refer to SiT2019 for -40°C to 125°C and SiT2021 for -55°C to 125°C options
- Excellent total frequency stability as low as ±20 PPM
- Low power consumption of 4.9 mA typical at 1.8V
- LVCMOS/LVTTL compatible output
- 5-pin SOT23-5: 2.9mm x 2.8mm
- RoHS and REACH compliant, Pb-free, Halogen-free and Antimony-free
- For AEC-Q100 oscillators, refer to SiT2024 and SiT2025

Applications

- GEPON, network switches, routers, servers, embedded systems, industrial and medical devices
- Ethernet, PCI-E, DDR, etc.







Electrical Specifications

Table 1. Electrical Characteristics

All Min and Max limits are specified over temperature and rated operating voltage with 15 pF output load unless otherwise stated. Typical values are at 25°C and nominal supply voltage.

Parameters	Symbol	Min.	Тур.	Max.	Unit	Condition			
			F	requency R	ange				
Output Frequency Range	f	115	-	137	MHz				
	Frequency Stability and Aging								
Frequency Stability	F_stab	-20	-	+20	PPM	Inclusive of Initial tolerance at 25°C, 1st year aging at 25°C, and			
		-25	-	+25	PPM	variations over operating temperature, rated power supply voltage and load (15 pF ± 10%).			
		-50	-	+50	PPM	,			
Operating Temperature Range									
Operating Temperature Range	T_use	-20	-	+70	°C	Extended Commercial			
(Ambient)		-40	-	+85	°C	Industrial			
		Sı	upply Voltag	e and Curr		ption			
Supply Voltage	Vdd	1.62	1.8	1.98	V				
		2.25	2.5	2.75	V				
		2.52	2.8	3.08	V				
		2.7	3.0	3.3	V				
		2.97	3.3	3.63	V				
		2.25	-	3.63	V				
Current Consumption	Idd	ı	6.2	7.5	mA	No load condition, f = 125 MHz, Vdd = 2.8V, 3.0V, 3.3V or 2.25 to 3.63V			
		-	5.5	6.4	mA	No load condition, f = 125 MHz, Vdd = 2.5V			
		-	4.9	5.6	mA	No load condition, f = 125 MHz, Vdd = 1.8V			
OE Disable Current	l_od	-	-	4.3	mA	Vdd = 2.5V to 3.3V, OE = Low, Output in high Z state			
		-	-	4.1	mA	Vdd = 1.8V, OE = Low, Output in high Z state			
Standby Current	I_std	-	2.6	4.3	μА	Vdd = 2.8V to 3.3V, \overline{ST} = Low, Output is weakly pulled down			
		-	1.4	2.5	μΑ	Vdd = 2.5V, \overline{ST} = Low, Output is weakly pulled down			
		-	0.6	1.3	μΑ	Vdd = 1.8V, ST = Low, Output is weakly pulled down			
			LVCMOS	Output Ch	aracteristic	s			
Duty Cycle	DC	45	-	55	%	All Vdds			
Rise/Fall Time	Tr, Tf	1	1.0	2.0	ns	Vdd = 2.5V, 2.8V, 3.0V or 3.3V, 20% - 80%			
		1	1.3	2.5	ns	Vdd =1.8V, 20% - 80%			
		1	1.0	2.0	ns	Vdd = 2.25V - 3.63V, 20% - 80%			
Output High Voltage	VOH	90%	-	-	Vdd	IOH = -4 mA (Vdd = 3.0V or 3.3V) IOH = -3 mA (Vdd = 2.8V and Vdd = 2.5V) IOH = -2 mA (Vdd = 1.8V)			
Output Low Voltage	VOL	-	-	10%	Vdd	IOL = 4 mA (Vdd = 3.0V or 3.3V) IOL = 3 mA (Vdd = 2.8V and Vdd = 2.5V) IOL = 2 mA (Vdd = 1.8V)			
			Inp	ut Characte	ristics				
Input High Voltage	VIH	70%	-	-	Vdd	Pin 1, OE or ST			
Input Low Voltage	VIL	-	-	30%	Vdd	Pin 1, OE or ST			
Input Pull-up Impedance	Z_in	50	87	150	kΩ	Pin 1, OE logic high or logic low, or ST logic high			
		2	-	_	MΩ	Pin 1, ST logic low			

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High Frequency, Single Chip, One-output Clock Generator



Table 1. Electrical Characteristics (continued)

Parameters	Symbol	Min.	Тур.	Max.	Unit	Condition		
Startup and Resume Timing								
Startup Time	T_start	_	-	5	ms	Measured from the time Vdd reaches its rated minimum value		
Enable/Disable Time	T_oe	_	-	130	ns	f = 115 MHz. For other frequencies, T_oe = 100 ns + 3 * clock periods		
Resume Time	T_resume	_	-	5	ms	Measured from the time ST pin crosses 50% threshold		
			•	Jitter				
RMS Period Jitter	T_jitt	-	1.9	3	ps	f = 125 MHz, Vdd = 2.5V, 2.8V, 3.0V or 3.3V		
		-	1.6	4	ps	f = 125 MHz, Vdd = 1.8V		
Peak-to-peak Period Jitter	T_pk	_	12	20	ps	f = 125 MHz, Vdd = 2.5V, 2.8V, 3.0V or 3.3V		
		-	14	30	ps	f = 125 MHz, Vdd = 1.8V		
RMS Phase Jitter (random)	T_phj	-	0.5	0.9	ps	Integration bandwidth = 900 kHz to 7.5 MHz		
		_	1.3	2	ps	Integration bandwidth = 12 kHz to 20 MHz		

Table 2. Pin Description

Pin	Symbol		Functionality		
1	GND	Power	Electrical ground		
2	NC	No Connect	No connect		
		Output Enable	H ^[1] : specified frequency output L: output is high impedance. Only output driver is disabled.		
3	3 OE/ ST/NC Standby No Connect		H or Open ^[1] : specified frequency output L: output is low (weak pull down). Device goes to sleep mode. Supply current reduces to I_std.		
			Any voltage between 0 and Vdd or Open ^[1] : Specified frequency output. Pin 3 has no function.		
4	VDD	Power	Power supply voltage ^[2]		
5	OUT	Output	Oscillator output		

Notes:

- In OE or ST mode, a pull-up resistor of 10 kΩ or less is recommended if pin 3 is not externally driven. If pin 3 needs to be left floating, use the NC option.
 A capacitor of value 0.1 μF or higher between Vdd and GND is required.

Top View

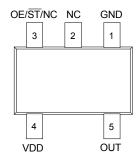


Figure 1. Pin Assignments

High Frequency, Single Chip, One-output Clock Generator



Table 3. Absolute Maximum Limits

Attempted operation outside the absolute maximum ratings of the part may cause permanent damage to the part. Actual performance of the IC is only guaranteed within the operational specifications, not at absolute maximum ratings.

Parameter	Min.	Max.	Unit
Storage Temperature	-65	150	°C
Vdd	-0.5	4	V
Electrostatic Discharge	-	2000	V
Soldering Temperature (follow standard Pb free soldering guidelines)	-	260	°C
Junction Temperature ^[3]	-	150	°C

Note:

Table 4. Thermal Consideration^[4]

Package	θ _{JA} , 4 Layer Board (°C/W)	θ _{JC} , Bottom (°C/W)
SOT23-5	421	175

Note:

Table 5. Maximum Operating Junction Temperature^[5]

Max Operating Temperature	Maximum Operating Junction Temperature		
70°C	80°C		
85°C	95°C		

Note:

Table 6. Environmental Compliance

Parameter	Condition/Test Method
Mechanical Shock	MIL-STD-883F, Method 2002
Mechanical Vibration	MIL-STD-883F, Method 2007
Temperature Cycle	JESD22, Method A104
Solderability	MIL-STD-883F, Method 2003
Moisture Sensitivity Level	MSL1 @ 260°C

^{3.} Exceeding this temperature for extended period of time may damage the device.

^{4.} Refer to JESD51 for θ_{JA} and θ_{JC} definitions, and reference layout used to determine the θ_{JA} and θ_{JC} values in the above table.

^{5.} Datasheet specifications are not guaranteed if junction temperature exceeds the maximum operating junction temperature.

High Frequency, Single Chip, One-output Clock Generator



Test Circuit and Waveform^[6]

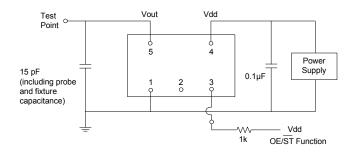


Figure 2. Test Circuit

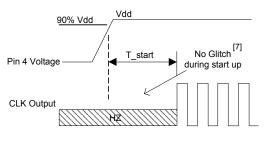
Note:

6. Duty Cycle is computed as Duty Cycle = TH/Period.

Tr — Tf 80% Vdd 50% 20% Vdd High Pulse (TH) Period Period

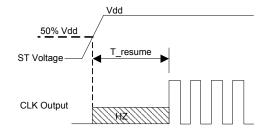
Figure 3. Output Waveform

Timing Diagrams



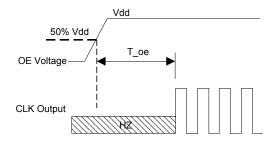
T_start: Time to start from power-off

Figure 4. Startup Timing (OE/ST Mode)



T_resume: Time to resume from ST

Figure 5. Standby Resume Timing (ST Mode Only)

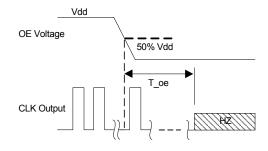


T_oe: Time to re-enable the clock output

Figure 6. OE Enable Timing (OE Mode Only)

Note:

7. SiT2002 has "no runt" pulses and "no glitch" output during startup or resume.



T_oe: Time to put the output in High Z mode

Figure 7. OE Disable Timing (OE Mode Only)

High Frequency, Single Chip, One-output Clock Generator



Performance Plots^[8]

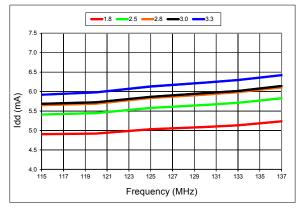


Figure 8. Idd vs Frequency

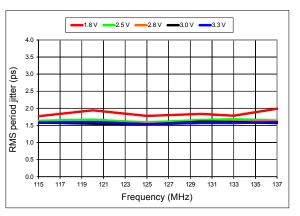


Figure 10. RMS Period Jitter vs Frequency

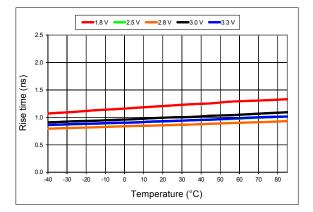


Figure 12. 20%-80% Rise Time vs Temperature

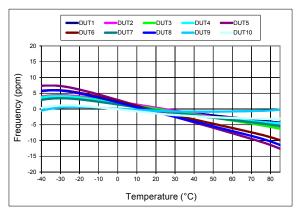


Figure 9. Frequency vs Temperature, 1.8V

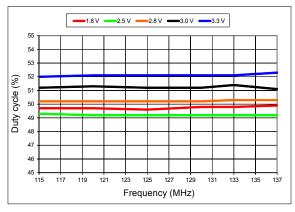


Figure 11. Duty Cycle vs Frequency

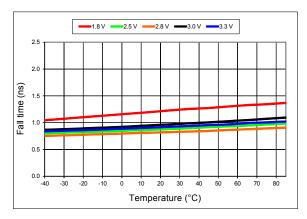


Figure 13. 20%-80% Fall Time vs Temperature

High Frequency, Single Chip, One-output Clock Generator



Performance Plots^[8]

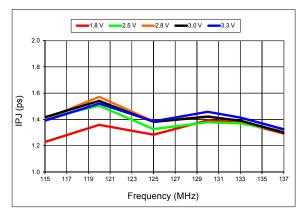


Figure 14. RMS Integrated Phase Jitter Random (12 kHz to 20 MHz) vs Frequency^[9]

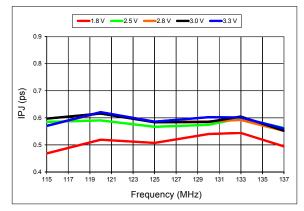


Figure 15. RMS Integrated Phase Jitter Random (900 kHz to 20 MHz) vs Frequency^[9]

Notes:

- 8. All plots are measured with 15 pF load at room temperature, unless otherwise stated.
- 9. Phase noise plots are measured with Agilent E5052B signal source analyzer.

High Frequency, Single Chip, One-output Clock Generator



Programmable Drive Strength

The SiT2002 includes a programmable drive strength feature to provide a simple, flexible tool to optimize the clock rise/fall time for specific applications. Benefits from the programmable drive strength feature are:

- Improves system radiated electromagnetic interference (EMI) by slowing down the clock rise/fall time.
- Improves the downstream clock receiver's (RX) jitter by decreasing (speeding up) the clock rise/fall time.
- Ability to drive large capacitive loads while maintaining full swing with sharp edge rates.

For more detailed information about rise/fall time control and drive strength selection, see the SiTime Application Notes section: http://www.sitime.com/support/application-notes.

EMI Reduction by Slowing Rise/Fall Time

Figure 16 shows the harmonic power reduction as the rise/fall times are increased (slowed down). The rise/fall times are expressed as a ratio of the clock period. For the ratio of 0.05, the signal is very close to a square wave. For the ratio of 0.45, the rise/fall times are very close to near-triangular waveform. These results, for example, show that the 11th clock harmonic can be reduced by 35 dB if the rise/fall edge is increased from 5% of the period to 45% of the period.

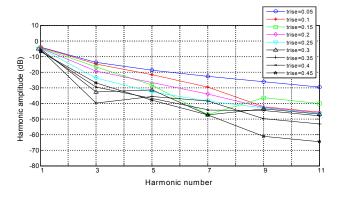


Figure 16. Harmonic EMI reduction as a Function of Slower Rise/Fall Time

Jitter Reduction with Faster Rise/Fall Time

Power supply noise can be a source of jitter for the downstream chipset. One way to reduce this jitter is to speed up the rise/fall time of the input clock. Some chipsets may also require faster rise/fall time in order to reduce their sensitivity to this type of jitter. Refer to the Rise/Fall Time Tables (Table 7 to Table 11) to determine the proper drive strength.

High Output Load Capability

The rise/fall time of the input clock varies as a function of the actual capacitive load the clock drives. At any given drive strength, the rise/fall time becomes slower as the output load increases. As an example, for a 3.3V SiT2002 device with default drive strength setting, the typical rise/fall time is 1ns for 15 pF output load. The typical rise/fall time slows down to 2.6 ns when the output load increases to 45 pF. One can choose to speed up the rise/fall time to 1.83 ns by then increasing the drive strength setting on the SiT2002.

The SiT2002 can support up to 30 pF maximum capacitive loads with drive strength settings. Refer to the Rise/Tall Time Tables (Table 7 to 11) to determine the proper drive strength for the desired combination of output load vs. rise/fall time.

SiT2002 Drive Strength Selection

Tables 7 through 11 define the rise/fall time for a given capacitive load and supply voltage.

- 1. Select the table that matches the SiT2002 nominal supply voltage (1.8V, 2.5V, 2.8V, 3.0V, 3.3V).
- Select the capacitive load column that matches the application requirement (5 pF to 30 pF)
- 3. Under the capacitive load column, select the desired rise/fall times.
- 4. The left-most column represents the part number code for the corresponding drive strength.
- Add the drive strength code to the part number for ordering purposes.

Calculating Maximum Frequency

Based on the rise and fall time data given in Tables 7 through 11, the maximum frequency the oscillator can operate with guaranteed full swing of the output voltage over temperature can be determined as follows:

$$Max Frequency = \frac{1}{5 \times Trf_{20/80}}$$

where Trf_20/80 is the typical value for 20%-80% rise/fall time.

Example 1

Calculate f_{MAX} for the following condition:

- Vdd = 3.3V (Table 11)
- · Capacitive Load: 30 pF
- Desired Tr/f time = 1.31 ns (rise/fall time part number code = F)

Part number for the above example:

SiT2002BIF12-18E-137.000000



Drive strength code is inserted here. Default setting is "-"

High Frequency, Single Chip, One-output Clock Generator



Rise/Fall Time (20% to 80%) vs C_{LOAD} Tables

Table 7. Vdd = 1.8V Rise/Fall Times for Specific C_{LOAD}

Rise/Fall Time Typ (ns)					
Drive Strength \ C LOAD 5 pF 15 pF 30 pF					
Т	0.93	n/a	n/a		
E	0.78	n/a	n/a		
U	0.70	1.48	n/a		
F or "-": default	0.65	1.30	n/a		

Table 8. Vdd = 2.5V Rise/Fall Times for Specific C_{LOAD}

Rise/Fall Time Typ (ns)						
Drive Strength \ C LOAD 5 pF 15 pF 30 pl						
R	1.45	n/a	n/a			
В	1.09	n/a	n/a			
Т	0.62	1.28	n/a			
E	0.54	1.00	n/a			
U or "-": default	0.43	0.96	n/a			
F	0.34	0.88	n/a			

Table 9. Vdd = 2.8V Rise/Fall Times for Specific C_{LOAD}

Rise/Fall Time Typ (ns)				
Drive Strength \ C _{LOAD}	5 pF	15 pF	30 pF	
R	1.29	n/a	n/a	
В	0.97	n/a	n/a	
T	0.55	1.12	n/a	
E	0.44	1.00	n/a	
U or "-": default	0.34	0.88	n/a	
F	0.29	0.81	1.48	

Table 10. Vdd = 3.0V Rise/Fall Times for Specific C_{LOAD}

Rise/Fall Time Typ (ns)					
Drive Strength \ C _{LOAD}	5 pF	15 pF	30 pF		
R	1.22	n/a	n/a		
В	0.89	n/a	n/a		
T or "-": default	0.51	1.00	n/a		
E	0.38	0.92	n/a		
U	0.30	0.83	n/a		
F	0.27	0.76	1.39		

Table 11. Vdd = 3.3V Rise/Fall Times for Specific C_{LOAD}

Rise/Fall Time Typ (ns)					
Drive Strength \ C _{LOAD}	5 pF	15 pF	30 pF		
R	1.16	n/a	n/a		
В	0.81	n/a	n/a		
T or "-": default	0.46	1.00	n/a		
E	0.33	0.87	n/a		
U	0.28	0.79	1.46		
F	0.25	0.72	1.31		

Note:

^{10. &}quot;n/a" in Table 7 to Table 11 indicates that the resulting rise/fall time from the respective combination of the drive strength and output load does not provide rail-to-rail swing and is not available.

High Frequency, Single Chip, One-output Clock Generator



Pin 3 Configuration Options (OE, ST or NC)

Pin 3 of the SiT2002 can be factory-programmed to support three modes: Output Enable (OE), standby (\overline{ST}) or No Connect (NC). These modes can also be programmed with the Time Machine using field programmable devices.

Output Enable (OE) Mode

In the OE mode, applying logic Low to the OE pin only disables the output driver and puts it in Hi-Z mode. The core of the device continues to operate normally. Power consumption is reduced due to the inactivity of the output. When the OE pin is pulled High, the output is typically enabled in $<1\mu$ s.

Standby (ST) Mode

In the \overline{ST} mode, a device enters into the standby mode when Pin 3 pulled Low. All internal circuits of the device are turned off. The current is reduced to a standby current, typically in the range of a few μA . When \overline{ST} is pulled High, the device goes through the "resume" process, which can take up to 5 ms.

No Connect (NC) Mode

In the NC mode, the device always operates in its normal mode and outputs the specified frequency regardless of the logic level on pin 3.

Table 12 below summarizes the key relevant parameters in the operation of the device in OE, \overline{ST} , or NC mode.

Table 12. OE vs. ST vs. NC

	OE	ST	NC
Active current 125 MHz (max, 1.8V)	5.6 mA	5.6 mA	5.6 mA
OE disable current (max. 1.8V)	4.1 mA	N/A	N/A
Standby current (typical 1.8V)	N/A	0.6 uA	N/A
OE enable time at 125 MHz (max)	130 ns	N/A	N/A
Resume time from standby (max, all frequency)	N/A	5 ms	N/A
Output driver in OE disable/standby mode	High Z	weak pull-down	N/A

Output on Startup and Resume

The SiT2002 comes with gated output. Its clock output is accurate to the rated frequency stability within the first pulse from initial device startup or resume from the standby mode.

In addition, the SiT2002 supports "no runt" pulses and "no glitch" output during startup or resume as shown in the waveform captures in Figure 17 and Figure 18.

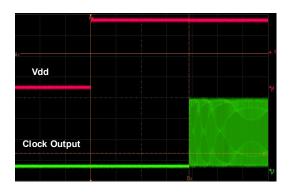


Figure 17. Startup Waveform vs. Vdd

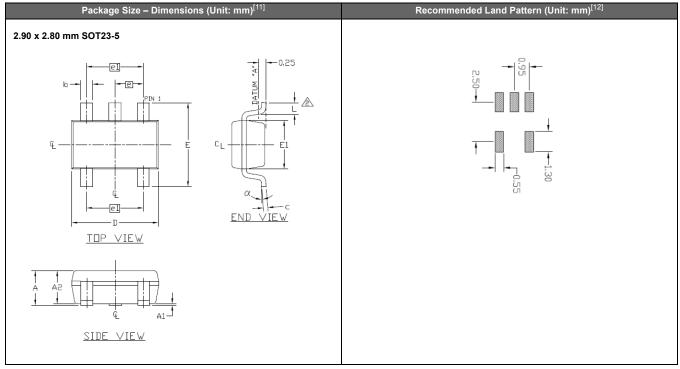


Figure 18. Startup Waveform vs. Vdd (Zoomed-in View of Figure 17)

High Frequency, Single Chip, One-output Clock Generator



Dimensions and Patterns



Notes:

11.Top marking: Y denotes manufacturing origin and XXXX denotes manufacturing lot number. The value of "Y" will depend on the assembly location of the device.

12. A capacitor value of 0.1 µF between Vdd and GND is required.

Table 13. Dimension Table

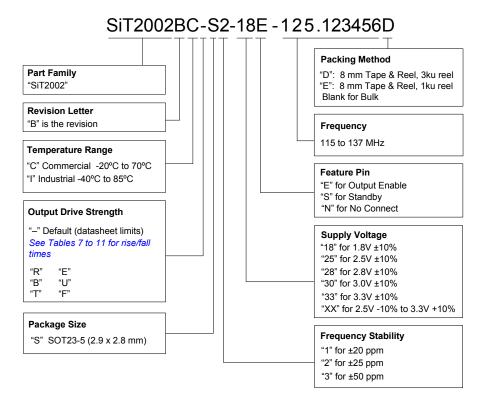
Symbol	Min.	Nom.	Max.
Α	0.90	1.25	1.45
A1	0.00	0.05	0.15
A2	0.90	1.10	1.30
b	0.35	0.40	0.50
С	0.08	0.15	0.20
D	2.80	2.90	3.00
E	2.60	2.80	3.00
E1	1.50	1.625	1.75
L	0.35	0.45	0.60
L1	0.60 REF		
е	0.95 BSC.		
e1	1.90 BSC.		
α	0°	2.5°	8°

High Frequency, Single Chip, One-output Clock Generator



Ordering Information

The Part No. Guide is for reference only. To customize and build an exact part number, use the SiTime <u>Part Number</u> <u>Generator.</u>



High Frequency, Single Chip, One-output Clock Generator



Table 14. Additional Information

Document	Description	Download Link	
Time Machine II	MEMS oscillator programmer	http://www.sitime.com/support/time-machine-oscillator-programmer	
Field Programmable Oscillators	Devices that can be programmable in the field by Time Machine II	http://www.sitime.com/products/field-programmable-oscillators	
Manufacturing Notes	Tape & Reel dimension, reflow profile and other manufacturing related info	http://www.sitime.com/component/docman/doc_download/243-manufacturing-notes-for-sitime-oscillator	
Qualification Reports	RoHS report, reliability reports, composition reports	http://www.sitime.com/support/quality-and-reliability	
Performance Reports	Additional performance data such as phase noise, current consumption and jitter for selected frequencies		
Termination Techniques	Termination design recommendations	http://www.sitime.com/support/application-notes	
Layout Techniques	Layout recommendations	http://www.sitime.com/support/application-notes	

Revision History

Table 15. Datasheet Version and Change Log

Version	Release Date	Change Summary
1.0	5/14/15	Final Production Release.

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